

TEST RESULTS[®]

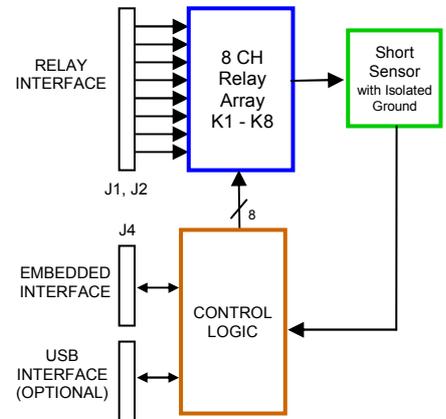
Test Results[®], is a company news periodical published by Overton Instruments (Oi), to highlight new products, special events and noteworthy Functional Test solutions. Customer names may be disguised for identity protection. 1/27/17

Low cost Short-Finder module, adds ICT measurements to Functional Test equipment...

Presented by,
Overton Claborne Sr
(Oi) Founder & CEO



SFM-MATE



Because of constant budget limitations, Test Engineers are often confronted with a critical decision - do I implement an ICT or Functional Test strategy to verify a PCBA in Manufacturing? With the introduction of the SFM-MATE^(vi), Test Engineers can now bring ICT-like capability into the Functional Test domain.

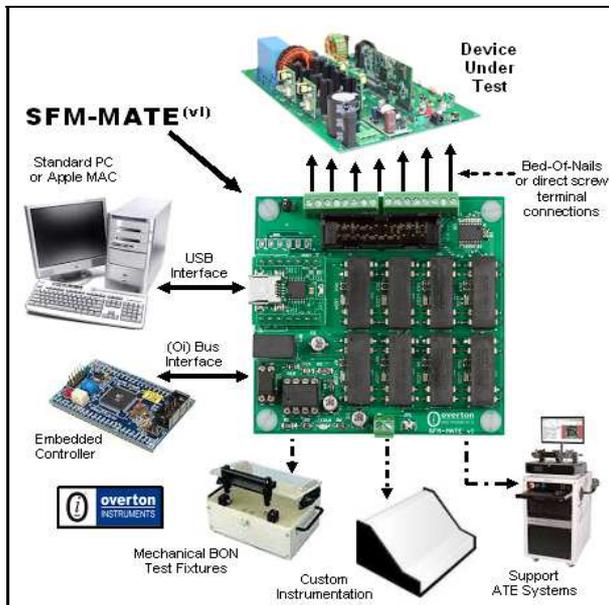
The SFM-MATE^(vi) is a unique instrument module that adds a special short-finder capability to custom Functional Test equipment.

Rather than spending thousands of dollars to test all nodes on a PCB, the SFM-MATE^(vi) limits the number of test points to those defined as "high-risk". Examples of high-risk test points would include DUT power rails, voltage regulators & references, power devices, system clocks, reset circuits and many others. Prior to applying DUT power, the SFM-MATE^(vi) can quickly identify electrical hazards which could cause damage to the DUT, adjoining test equipment or injury to the Test Operator.

In the illustration above, the versatility of the SFM-MATE^(vi) is on full display.

The SFM-MATE^(vi) can be used to enhance Mechanical Test Fixtures, quickly create custom instrumentation or support larger ATE test systems. There are two options for external control, with a standard PC or use one of our Embedded Test Controllers (i.e., the Pico-MATE). Connection to the DUT (device-under-test), is made possible by two methods. First, with a collection of screw terminal connections, and second, a 20-pin header. The header consolidates the input channels and provides a convenient method to cable over to an array of spring probes in a test fixture. Power for the SFM-MATE^(vi), is provided by the USB bus or through the (Oi) Bus port (no independent power source is required).

Rather than spending thousands of dollars for a single ICT solution, the SFM-MATE^(vi) expands the capability of Functional Test, all for a fraction of the cost.



Special Features

- ▶ Unique sensor-circuit that detect shorts or opens on 8 independent channels
- ▶ Scan all channels in less than 40msec
- ▶ Externally controlled by a PC (via USB), or with an embedded controller (i.e., the Pico-MATE)
- ▶ Connect to the DUT via screw terminals or with a ribbon cable assembly
- ▶ Compact size, just 2.50" x 2.75"
- ▶ Low cost, just \$149 single qty

Unique Benefits

- ▶ Enhance Functional Test equipment by adding ICT-like capability
- ▶ Avoid electrical hazards by detecting shorts before applying DUT power
- ▶ Install inside Mechanical Test Fixtures, create custom instrumentation or support larger ATE test systems
- ▶ Easy expansion, use the mounting holes to stack several modules together
- ▶ PC control is simple, just use the USB port to issue a set of ASCII commands



Dave Gingerella
Owner/Manager



We are extremely pleased to announce the addition of Test-X Fixture Products to our growing list of qualified VAR's, Value Added Resellers. For the past 30 years Test-X (led by Dave Gingerella), has built thousands of custom test fixtures for top companies all over the world. According to Dave, "there is no question about it, (Oi) Functional Test enhancement products will make a significant contribution to my efforts to deliver high-quality test solutions to my customer base". Dave can be reached at 951-688-3067, or dave@test-x.com.